

BSDS (2024, Semester II): Statistics II

Mid-semester Examination

NAME :

ROLL :

Time: 120 minutes

Total attainable marks: 30

1. Let X_1, \dots, X_n be a random sample from exponential distribution with pdf

$$f_\lambda(x) = \lambda \exp\{-\lambda x\}, \quad x > 0, \quad \lambda > 0.$$

Consider the parameter of interest $\psi(\lambda) = \frac{\lambda}{1 + \lambda}$.

- (a) Find an MLE of $\psi(\lambda)$, say $T_{MLE,n}$.

[4]

We first find the MLE of λ .

The log-likelihood function

$$\begin{aligned} \ln(\lambda | \underline{x}_n) &= \log \left(\lambda^n e^{-\lambda \sum_{i=1}^n x_i} \right) \\ &= n \log \lambda - \lambda \sum_{i=1}^n x_i \end{aligned}$$

First order equation:

$$\frac{\partial \ln(\lambda | \underline{x}_n)}{\partial \lambda} = 0 \Rightarrow \frac{n}{\lambda} - n \bar{x}_n = 0 \Rightarrow \hat{\lambda} = \frac{1}{\bar{x}_n}.$$

Second order condition:

$$\left. \frac{\partial^2 \ln(\lambda | \underline{x}_n)}{\partial \lambda^2} \right|_{\lambda=\hat{\lambda}} = -\frac{n}{\hat{\lambda}^2} = -n \bar{x}_n^2 < 0$$

Thus, $\hat{\lambda}_{MLE} = \frac{1}{\bar{x}_n}$.

By the invariance property of MLE, MLE of $\psi(\lambda)$ is:

$$T_{MLE,n} = \psi(\hat{\lambda}_{MLE}) = \frac{\hat{\lambda}_{MLE}}{1 + \hat{\lambda}_{MLE}} = \frac{1}{\bar{x}_n + 1}.$$

(b) Show that S_n/n is consistent for $1/\lambda$.

[4]

Here $S_n = x_1 + \dots + x_n$ and $S_n/n = \bar{x}_n$.

Now, $E(\bar{x}_n) = E(x_1) = \int_0^\infty \lambda x e^{-\lambda x} dx$

$$= \int_0^\infty \frac{1}{\lambda} u e^{-u} du \quad \text{where } \lambda x = u$$
$$= \frac{1}{\lambda} \Gamma(2) = \frac{1}{\lambda}$$

By Weak Law of Large Numbers (WLLN) we know that when x_1, \dots, x_n are IID samples with finite variances,

then $\bar{x}_n \xrightarrow{P} 1/\lambda$.

Here $\text{var}(\bar{x}_n) = \frac{\text{var}(x_1)}{n}$.

Further, $\text{var}(x_1) = E(x_1^2) - \frac{1}{\lambda^2}$

$$= \int_0^\infty \lambda x^2 e^{-\lambda x} dx - \frac{1}{\lambda^2}$$
$$= \frac{1}{\lambda^2} \int_0^\infty u^2 e^{-u} du - \frac{1}{\lambda^2}$$
$$= \frac{\Gamma(3)}{\lambda^2} - \frac{1}{\lambda^2} = \frac{1}{\lambda^2} < \infty$$

So, \bar{x}_n is consistent for $1/\lambda^2$.

Is $T_{MLE,n}$ consistent for $\psi(\lambda)$?

[4]

As $g(x) = \frac{1}{x+1}$ is a continuous function of x on $(0, \infty)$,
by continuous mapping theorem,
if $\bar{x}_n \xrightarrow{P} \gamma_n$
then $g(\bar{x}_n) \xrightarrow{P} g(\gamma_n)$.

Further, as $g(\bar{x}_n) = T_{MLE,n}$, and $g(\gamma_n) = \frac{1}{1+\gamma_n} = \psi(\lambda)$,
 $T_{MLE,n}$ is consistent for $\psi(\lambda)$.

(c) Consider another estimator of $\psi(\lambda)$ as $W_n = \frac{1}{n} \sum_{i=1}^n \exp\{-X_i\}$.

i. Show that W_n is unbiased for $\psi(\lambda)$. [4]

$$E(W_n) = \frac{1}{n} \sum_{i=1}^n E(\bar{e}^{-x_i}) = E(\bar{e}^{-x_1})$$

$$\begin{aligned} \text{Now, } E(\bar{e}^{-x_1}) &= \int_0^\infty \lambda e^{-x} e^{-\lambda x} dx \\ &= \lambda \int_0^\infty e^{-(1+\lambda)x} dx \\ &= \frac{\lambda}{1+\lambda} \int_0^\infty e^{-u} du \quad \text{where } u = (1+\lambda)x \\ &= \frac{\lambda}{1+\lambda} = \psi(\lambda). \end{aligned}$$

Thus, W_n is an unbiased estimator of $\psi(\lambda)$.

ii. Is \hat{W}_n consistent for $\psi(\theta)$? $\psi(\lambda)$?

[4]

For $i=1,\dots,n$, define $W_i = \frac{-x_i}{e}$. Then $\hat{W}_n = \frac{1}{n} \sum_{i=1}^n W_i$.

By WLLN,

$$\hat{W}_n \xrightarrow{P} E(W_i) = \psi(\lambda),$$

provided $\text{var}(W_i) < \infty$.

$$\begin{aligned} \text{Here } \text{var}(W_i) &= E(W_i^2) - \psi^2(\lambda) \\ &= \lambda \int_0^\infty e^{-2x-\lambda x} dx - \frac{\lambda}{1+\lambda} \\ &= \frac{\lambda}{(\lambda+2)} \int_0^\infty e^{-u} du - \frac{\lambda^2}{(1+\lambda)^2}, \\ &\quad \text{where } u = (\lambda+2)x. \\ &= \frac{\lambda}{\lambda+2} - \frac{\lambda^2}{(\lambda+1)^2} \\ &= \frac{\lambda(\lambda^2+2\lambda+1-\lambda^2-2\lambda)}{(\lambda+1)^2(\lambda+2)} \\ &= \frac{\lambda}{(\lambda+1)^2(\lambda+2)} < \infty. \end{aligned}$$

So, \hat{W}_n is consistent for $\psi(\lambda)$.

- iii. Find sequences of real numbers $\{a_n\}$ and $\{b_n\}$ such that $\frac{W_n - a_n}{b_n} \xrightarrow{d} X$, where $X \sim N(0, 1)$ distribution. [Hint: Apply CLT] [4]

By Central Limit Theorem (CLT) we have

$$\frac{\sqrt{n} (W_n - E(W_1))}{\sqrt{\text{var}(W_1)}} \xrightarrow{d} X,$$

where $X \sim N(0, 1)$.

By the above calculations,

$$E(W_1) = \psi(\lambda),$$

$$\text{var}(W_1) = \frac{\psi''(\lambda)}{\lambda(\lambda+2)}$$

$$\therefore \frac{\sqrt{n} (W_n - \psi(\lambda))}{\sqrt{\psi''(\lambda)/\lambda(\lambda+2)}} \xrightarrow{d} X$$

So, $a_n = \psi(\lambda)$ for all n ,

$$\text{and } b_n = \frac{\psi(\lambda)}{\sqrt{n\lambda(\lambda+2)}}, \quad n \in \mathbb{N}.$$

2. Suppose the random measurements of a quantity is modeled as $\text{Gamma}(\alpha, \beta)$ with pdf

$$f_{\alpha, \beta}(x) = \frac{\beta^\alpha}{\Gamma \alpha} x^{\alpha-1} \exp\{-\beta x\}, \quad x > 0, \quad \alpha, \beta > 0.$$

Let the true measurement is α/β . If n independent measurements are taken, find the Uniformly Minimum Variance Unbiased Estimator (UMVUE)? [5]

Let x_1, \dots, x_n be the random variables indicating the independent measurements.

Then $x_i \stackrel{\text{iid}}{\sim} \text{Gamma}(\alpha, \beta); i=1, \dots, n$

To find the UMVUE of α/β , we first find a complete sufficient statistic (css) for the family.

Observe that,

$$\begin{aligned} f_{\alpha, \beta}(\mathbf{x}) &= \frac{\beta^{n\alpha}}{(\Gamma \alpha)^n} \left(\prod_{i=1}^n x_i \right)^{\alpha-1} e^{-\beta \sum_{i=1}^n x_i} \\ &= \exp \left\{ -n \log \beta - n \log \Gamma \alpha + (\alpha-1) \sum_{i=1}^n \log x_i - \beta \sum_{i=1}^n x_i \right\} \\ &= \exp \left\{ \alpha(\alpha, \beta) + h(\mathbf{x}) + T_1(\mathbf{x}) K_1(\alpha, \beta) + T_2(\mathbf{x}) K_2(\alpha, \beta) \right\} \end{aligned}$$

with $\alpha(\alpha, \beta) = n \log \beta - n \log \Gamma \alpha$

$$h(\mathbf{x}) = 0$$

$$T_1(\mathbf{x}) = \sum_{i=1}^n \log x_i$$

$$K_1(\alpha, \beta) = (\alpha-1)$$

$$T_2(\mathbf{x}) = \sum_{i=1}^n x_i$$

$$\text{and } K_2(\alpha, \beta) = -\beta.$$

Thus, $T(\mathbf{x}) = \left(\sum_{i=1}^n \log x_i, \sum_{i=1}^n x_i \right)'$ is jointly css.

Next, observe that,

$$\begin{aligned} E(x_1) &= \int_0^\infty \frac{\beta^\alpha}{\Gamma(\alpha)} x^\alpha e^{-\beta x} dx \\ &= \int_0^\infty \frac{1}{\beta \Gamma(\alpha)} u^\alpha e^{-u} du \quad \text{where } u = \beta x \\ &= \frac{\Gamma(\alpha+1)}{\beta \Gamma(\alpha)} = \frac{\alpha}{\beta}. \end{aligned}$$

Therefore, $E\left(\frac{1}{n} \sum_{i=1}^n x_i\right) = \frac{\alpha}{\beta}.$

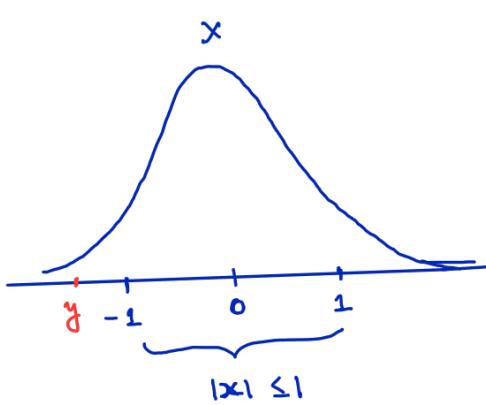
So, the statistic $\bar{x}_n = \frac{1}{n} \sum_{i=1}^n x_i = g(\bar{x})$ is
a function of a CSS (here, $g(\bar{x}) = \bar{x}/n$), and
is unbiased for α/β . So, \bar{x}_n is the UMVUE of α/β .

3. Let $X \sim \text{normal}(0, 1)$. Define $Y = -X\mathbb{I}(|X| \leq 1) + X\mathbb{I}(|X| > 1)$. Find the distribution of Y . [5]

Observe that $y = x$ when $x > 1$ or $x < -1$

and $y = -x$ when $-1 \leq x \leq 1$.

We will find the CDF of y , say F_y .



Let $-\infty < y < 1$,

$$\begin{aligned} \text{then } F_y(y) &= P(Y \leq y) \\ &= P(x \leq y) = \Phi(y) \quad \text{--- ①} \end{aligned}$$

Let $-1 \leq y \leq 1$,

$$\begin{aligned} \text{then } F_y(y) &= P(Y \leq -1) + P(-1 \leq Y \leq y) \\ &= P(x \leq -1) + P(-1 \leq -x \leq y) \\ &= \Phi(-1) + P(-y \leq x \leq 1) \\ &= \Phi(-1) + \Phi(1) - \Phi(-y) \\ &= 1 - \Phi(1) + \Phi(1) - 1 + \Phi(y) \\ &\quad \text{as } \Phi(-z) = 1 - \Phi(z) \\ &= \Phi(y) \quad \text{--- ②} \end{aligned}$$

Let $y > 1$, then

$$\begin{aligned} F_y(y) &= P(Y \leq 1) + P(1 < Y \leq y) \\ &= \Phi(1) + P(1 < x \leq y) \quad \text{from ②} \\ &= \Phi(1) + \Phi(y) - \Phi(1) \\ &= \Phi(y) \quad \text{--- ③} \end{aligned}$$

Combining ①-③ we get $F_y(\cdot) = \Phi(\cdot)$. So, $Y \sim N(0, 1)$.

4. A factory produces electronic components, and the number of defective components produced by each machine per day follows a Poisson distribution with a mean of 4 defectives. If 50 machines are in operation, what is the probability that the total number of defectives produced by all machines in a day is between 180 and 200? [You may use the fact $\Phi(\sqrt{2}) = 0.9214$.] [6]

Let X_i be the random variable indicating the number of defective items produced by the i th machine in a day.
 $i=1, \dots, 50$

We assume, $X_i \stackrel{\text{iid}}{\sim} \text{Poisson}(\lambda)$ with $\lambda = 4$.

Need to calculate the probability,

$$P\left(180 \leq \sum_{i=1}^{50} X_i \leq 200\right).$$

By CLT,

$$\frac{S_n - E(S_n)}{\sqrt{\text{var}(S_n)}} \xrightarrow{d} X \text{ where } X \sim N(0,1),$$

where $E(S_n) = 50 \times 4$
 $\text{var}(S_n) = 50 \times 4$

$$\begin{aligned} & \therefore P(180 \leq S_n \leq 200) \\ &= P\left(\frac{180 - 200}{\sqrt{200}} \leq \frac{S_n - 200}{\sqrt{200}} \leq 0\right) \\ &= P\left(-\frac{20}{10\sqrt{2}} \leq \frac{S_n - 200}{10\sqrt{2}} \leq 0\right) \end{aligned}$$

$$= F_{Z_n}(0) - F_{Z_n}(-\sqrt{2}) \text{ where } Z_n = \frac{S_n - 200}{10\sqrt{2}}$$

$$\rightarrow \Phi(0) - \Phi(-\sqrt{2}) \text{ by CLT}$$

$$= 0.5 - [1 - \Phi(\sqrt{2})] = 0.9214 - 0.5 = \underline{\underline{0.4214}} \quad [\text{ANS}]$$

